

### Highlights:

- Two Day Event: 100+ Attendees
- Overview of TTTC India
- Insight into DFX as Career
- Lab Sessions
- Advanced DFX Topics



Test Seminar Participants



TTTC Overview: Navin Bishnoi



DFX as Career: Nagesh Tamarapalli



Lab Session: Venkata Totakura



Cell Aware Test: Subhadip Kundu



Evolution of Test: Abhishek Chaudhary



SDD Test: Ankush Srivastava



Automotive Test: Prasad Mantri

VLSI test seminar Bangalore, the second Test and Technology Technical Council (TTTC) India event was successfully conducted on 21<sup>st</sup> and 22<sup>nd</sup> of September at BMS Engineering college. The event was organized in collaboration with IEEE Bangalore section. The technical program was driven by TTTC India and the logistics were taken care of by IEEE Bangalore section. Agenda for the seminar was thoughtfully crafted to introduce participants to the basic of electronic test on the first day and then systematically expose them to the recent advances in the field on the second day. Lab session was introduced to allow the attendees an opportunity to glean hands-on experience. Seasoned speakers, including some of the industry veterans were identified to enlighten the attendees. Over hundred participants, both from academia and industry benefited from the seminar.

The General Chair of International Test Conference (ITC) India, Navin Bishnoi commenced the seminar by introducing the attendees to TTTC India and ITC India. This was followed by talk on “DFX as a Career: Choice or Compromise” by Nagesh Tamarapalli, an industry veteran and TTTC India Vice- Chair. The idea behind this presentation was to motivate the students and early career professionals by giving an insight into career prospects in electronic test. The session built momentum for the rest of the seminar and was received well by the audience. Thereafter, TTTC India Vice-Chair, Abhishek Chaudhary walked attendees through “Evolution of Test-Part 1”, wherein he covered need for electronic test, test challenges, basics of scan and scan compression. The session was interactive, questions related to Automatic Test Equipment (ATE), wafer probe and test head clearly reflected the curiosity level of the audience. ITC India Steering Committee member, Prof. Sivanatham maintained the momentum as he presented “Evolution of Test-Part 2” and touched on MBIST and IEEE 1149.1.

Lab session and advanced topics made the second day of the conference equally exciting for the participants. The second day started with presentation on Cell-Aware-Test by Subhadip Kundu (Technical Lead-Qualcomm) and was followed by presentation on Small-Delay-Defect Test by Ankush Srivastava (Technical Lead-Qualcomm). Both the presentations were appreciated by the audience. In the second half, more than half of the participants benefited from carefully crafted lab session organized by Venkata Totakura, an industry veteran and Tutorial Chair of ITC India. Seasoned professional attended concurrent session on “Test Engineering Standards” and “Automotive Test” by Prasad Mantri, the General Co-Chair of ITC India and an industry veteran. The session was enlightening and was very well received by attendees.

The feedback from the attendees was captured using a survey. The response received reflected that the participants found the seminar useful and informative. As expected, the lab session was the differentiating factor and was highly appreciated by the participants.

TTTC India would like to express gratitude to IEEE Bangalore Section and BMS Engineering College for flawless help on logistics. TTTC India would like to thank Abhishek Appaji, Assistant Professor BMS Engineering College and Sight Chair IEEE Bangalore Section, for a highly productive month-long collaboration.